High Voltage SWITCHMODE Series DPAK For Surface Mount Applications

This device is designed for high-voltage, high-speed power switching inductive circuits where fall time is critical. It is particularly suited for 115 and 220 V SWITCHMODE applications such as switching regulators, inverters, motor controls, solenoid/relay drivers and deflection circuits.

- Lead Formed for Surface Mount Applications in Plastic Sleeves (No Suffix)
- Straight Lead Version in Plastic Sleeves ("-1" Suffix)
- Lead Formed Version in 16 mm Tape and Reel ("T4" Suffix)
- Reverse Biased SOA with Inductive Loads @ $T_C = 100$ °C
- Inductive Switching Matrix 0.5 to 1.5 Amp, 25 and 100 °C . . .

t_c @ 1.0 A, 100°C is 290 ns (Typ)

- 700 V Blocking Capability
- Switching and SOA Applications Information
- Electrically Similar to the Popular MJE13003

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector–Emitter Voltage	V _{CEO(sus)}	400	Vdc
Collector–Emitter Voltage	V _{CEV}	700	Vdc
Emitter Base Voltage	V _{EBO}	9	Vdc
Collector Current — Continuous — Peak (1)	I _C	1.5 3	Adc
Base Current — Continuous — Peak (1)	I _B	0.75 1.5	Adc
Emitter Current — Continuous — Peak (1)	I _E	2.25 4.5	Adc
Total Power Dissipation @ T _A = 25°C (2) Derate above 25°C	P _D	1.56 0.0125	Watts W/°C
Total Power Dissipation @ T _C = 25°C Derate above 25°C	P _D	15 0.12	Watts W/°C
Operating and Storage Junction Temperature Range	T _J , T _{stg}	-65 to +150	°C

THERMAL CHARACTERISTICS

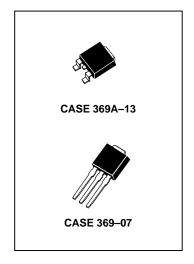
Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	8.33	°C/W
Thermal Resistance, Junction to Ambient (2)	$R_{\theta JA}$	80	°C/W
Maximum Lead Temperature for Soldering Purposes	TL	260	°C

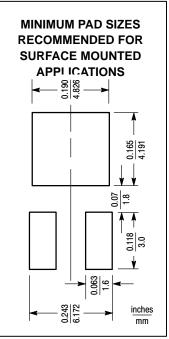
- (1) Pulse Test: Pulse Width = 5 ms, Duty Cycle \leq 10%.
- (2) When surface mounted on minimum pad sizes recommended.

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MJD13003

NPN SILICON
POWER TRANSISTOR
1.5 AMPERES
400 VOLTS
15 WATTS





ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERISTICS	6 (1)					
Collector–Emitter Sustai (I _C = 10 mA, I _B = 0)	V _{CEO(sus)}	400	_	_	Vdc	
Collector Cutoff Current (V _{CEV} = Rated Value, (V _{CEV} = Rated Value,	ICEV	_		0.1 2	mAdc	
Emitter Cutoff Current (V _{EB} = 9 Vdc, I _C = 0)		I _{EBO}	_	_	1	mAdc
SECOND BREAKDOWN						
Second Breakdown Coll	ector Current with Base Forward Biased	I _{S/b}	S	ee Figure	11	
Clamped Inductive SOA	with Base Reverse Biased	RBSOA	S	ee Figure	12	
ON CHARACTERISTICS	(1)					•
DC Current Gain (I _C = 0.5 Adc, V _{CE} = 2 (I _C = 1 Adc, V _{CE} = 2 \	h _{FE}	8 5	_ _	40 25	_	
$ \begin{aligned} &\text{Collector-Emitter Satura} \\ &\text{(I}_{\text{C}} = 0.5 \text{ Adc, I}_{\text{B}} = 0.1 \\ &\text{(I}_{\text{C}} = 1 \text{ Adc, I}_{\text{B}} = 0.25 \\ &\text{(I}_{\text{C}} = 1.5 \text{ Adc, I}_{\text{B}} = 0.5 \\ &\text{(I}_{\text{C}} = 1 \text{ Adc, I}_{\text{B}} = 0.25 \end{aligned} $	V _{CE(sat)}	_ _ _ _	_ _ _ _	0.5 1 3 1	Vdc	
Base–Emitter Saturation ($I_C = 0.5 \text{ Adc}$, $I_B = 0.1$ ($I_C = 1 \text{ Adc}$, $I_B = 0.25$ ($I_C = 1 \text{ Adc}$, $I_B = 0.25$	V _{BE(sat)}	_ _ _	_ _ _	1 1.2 1.1	Vdc	
DYNAMIC CHARACTERI	STICS	<u> </u>				•
Current–Gain — Bandw (I _C = 100 mAdc, V _{CE} :		f _T	4	10	_	MHz
Output Capacitance (V _{CB} = 10 Vdc, I _E = 0,	f = 0.1 MHz)	C _{ob}	_	21	_	pF
SWITCHING CHARACTE	RISTICS					
Resistive Load (Table	1)	<u> </u>				
Delay Time		t _d		0.05	0.1	μs
Rise Time	$V_{CC} = 125 \text{ Vdc}, I_C = 1 \text{ A},$	t _r		0.5	1	μs
Storage Time	$I_{B1} = I_{B2} = 0.2 \text{ A}, t_p = 25 \mu\text{s},$ Duty Cycle 1%	t _s	_	2	4	μs
Fall Time		t _f	_	0.4	0.7	μs
Inductive Load, Clamp	ed (Table 1, Figure 13)		•	•	-	
Storage Time	Storage Time I _C = 1 A, V _{clamp} = 300 Vdc,			1.7	4	μs
Crossover Time	t _c	_	0.29	0.75	μs	
	$I_{B1} = 0.2 \text{ A}, V_{BE(off)} = 5 \text{ Vdc},$					

⁽¹⁾ Pulse Test: Pulse Width = 300 μs, Duty Cycle ≤ 2%.

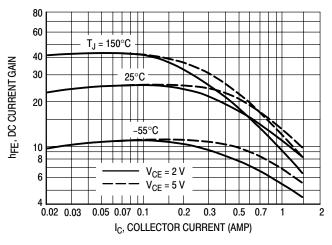


Figure 1. DC Current Gain

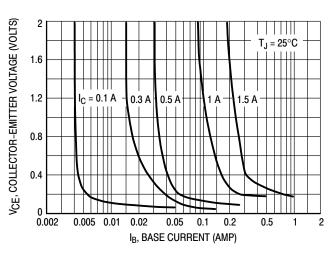


Figure 2. Collector Saturation Region

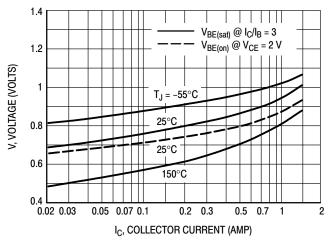


Figure 3. Base-Emitter Voltage

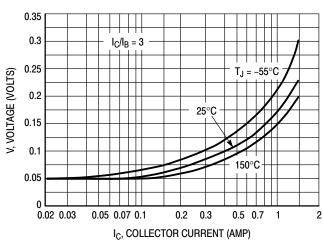


Figure 4. Collector-Emitter Saturation Region

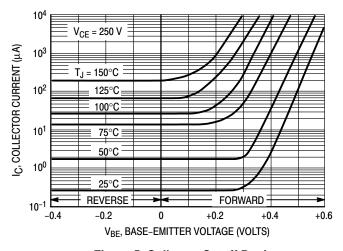


Figure 5. Collector Cutoff Region

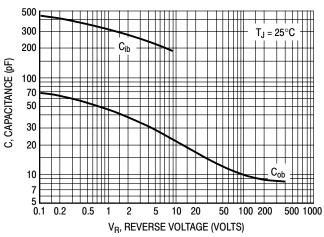


Figure 6. Capacitance

Table 1. Test Conditions For Dynamic Performance

	REVERSE BIAS SAFE OPERATING AREA AND INDUCTIVE SWITCHING	RESISTIVE SWITCHING
TEST CIRCUITS	DUTY CYCLE \leq 10% $_{1}$ $_{1}$ $_{2}$ $_{1}$ $_{3}$ $_{3}$ $_{1}$ $_{3}$ $_{3}$ $_{4}$ $_{5}$ $_{1}$ $_{5}$ $_{1}$ $_{1}$ $_{1}$ $_{5}$ $_{1}$ $_{1}$ $_{1}$ $_{2}$ $_{1}$ $_{1}$ $_{2}$ $_{1}$ $_{3}$ $_{4}$ $_{1}$ $_{2}$ $_{1}$ $_{2}$ $_{1}$ $_{2}$ $_{2}$ $_{1}$ $_{2}$ $_{3}$ $_{1}$ $_{2}$ $_{3}$ $_{3}$ $_{1}$ $_{3}$ $_{1}$ $_{3}$ $_{4}$ $_{3}$ $_{4}$ $_{5}$ $_{1}$ $_{1}$ $_{2}$ $_{$	+125 V D.U.T. RB SCOPE 1 -4 V
CIRCUIT	COIL DATA: GAP FOR 30 mH/2 V _{CC} = 20 V FERROXCUBE CORE #6656 A FULL BOBBIN (~200 TURNS) V _{clamp} = 300 Vdc #20 L _{coll} = 50 mH	$V_{CC} = 125 \text{ V}$ $R_C = 125 \Omega$ $D1 = 185820 \text{ OR EQUIV.}$ $R_B = 47 \Omega$
TEST WAVEFORMS	OUTPUT WAVEFORMS $ \begin{array}{c} I_{C} \\ I_{C(pk)} \\ \hline \\ V_{CE} \\ \hline \\ V_{Clamp} \\ \hline \\ IIM \\ \hline \\ E \\ \end{array} \begin{array}{c} t_{f} \\ \hline \\ t_{$	+10.3 25 μs V -8.5 V t _r , t _f < 10 ns DUTY CYCLE = 1.0% R _B AND R _C ADJUSTED FOR DESIRED I _B AND I _C

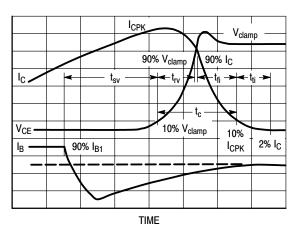


Figure 7. Inductive Switching Measurements

Table 2. Typical Inductive Switching Performance

I _C	T _C	t _{sv}	t _{rv}	t _{fi}	t _{ti}	t _c
AMP	°C	μ s	μ s	μs	μs	μ s
0.5	25	1.3	0.23	0.30	0.35	0.30
	100	1.6	0.26	0.30	0.40	0.36
1	25	1.5	0.10	0.14	0.05	0.16
	100	1.7	0.13	0.26	0.06	0.29
1.5	25	1.8	0.07	0.10	0.05	0.16
	100	3	0.08	0.22	0.08	0.28

NOTE: All Data Recorded in the Inductive Switching Circuit in Table 1

SWITCHING TIMES NOTE

In resistive switching circuits, rise, fall, and storage times have been defined and apply to both current and voltage waveforms since they are in phase. However, for inductive loads which are common to SWITCHMODE power supplies and hammer drivers, current and voltage waveforms are not in phase. Therefore, separate measurements must be made on each waveform to determine the total switching time. For this reason, the following new terms have been defined.

 t_{sv} = Voltage Storage Time, 90% I_{B1} to 10% V_{clamp}

 t_{rv} = Voltage Rise Time, 10–90% V_{clamp}

 t_{fi} = Current Fall Time, 90–10% I_{C}

 t_{ti} = Current Tail, 10–2% I_C

 t_c = Crossover Time, 10% V_{clamp} to 10% I_C

An enlarged portion of the inductive switching waveforms is shown in Figure 7 to aid in the visual identity of these terms.

For the designer, there is minimal switching loss during storage time and the predominant switching power losses occur during the crossover interval and can be obtained using the equation:

$$P_{SWT} = 1/2 V_{CC}I_{C}(t_{c})f$$

In general, $t_{rv} + t_{fi} \approx t_c$. However, at lower test currents this relationship may not be valid.

As is common with most switching transistors, resistive switching is specified at 25° C and has become a benchmark for designers. However, for designers of high frequency converter circuits, the user oriented specifications which make this a "SWITCHMODE" transistor are the inductive switching speeds (t_c and t_{sv}) which are guaranteed at 100° C.

RESISTIVE SWITCHING PERFORMANCE

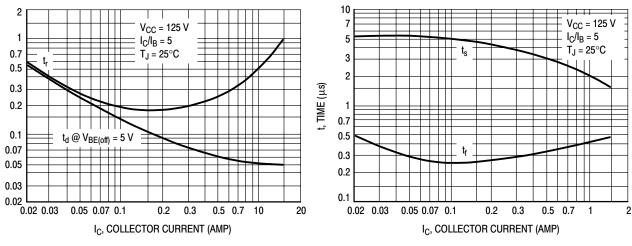


Figure 8. Turn-On Time

Figure 9. Turn-Off Time

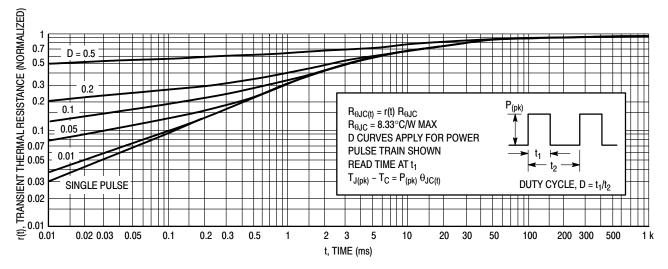


Figure 10. Thermal Response

The Sale Operating Area figures shown in Figures 11 and 12 are specified ratings for these devices under the test conditions shown.

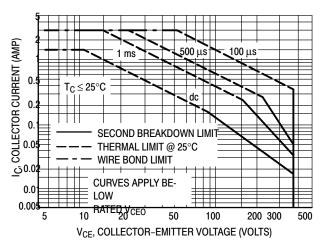


Figure 11. Active Region Safe Operating
Area

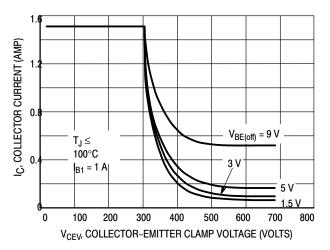


Figure 12. Reverse Bias Safe Operating Area

SAFE OPERATING AREA INFORMATION

FORWARD BIAS

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate $I_C - V_{CE}$ limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 11 is based on $T_C = 25^{\circ}C$; $T_{J(pk)}$ is variable depending on power level. Second breakdown pulse limits are valid for duty cycles to 10% but must be derated when $T_C \ge 25^{\circ}C$. Allowable current at the voltages shown on Figure 11 may be found at any case temperature by applying curves on Figure 13.

 $T_{J(pk)}$ may be calculated from the data in Figure 10. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

REVERSE BIAS

For inductive loads, high voltage and high current must be sustained simultaneously during turn-off, in most cases, with the base to emitter junction reverse biased. Under these conditions the collector voltage must be held to a safe level at or below a specific value of collector current. This can be accomplished by several means such as active clamping, RC snubbing, load line shaping, etc. The safe level for these devices is specified as Reverse Bias Safe Operating Area and represents the voltage-current conditions during reverse biased turn-off. This rating is verified under clamped conditions so that the device is never subjected to an avalanche mode. Figure 12 gives RBSOA characteristics.

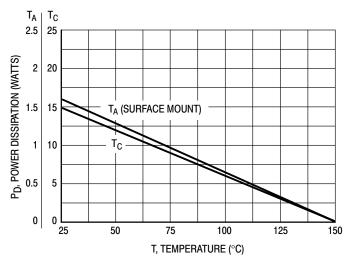
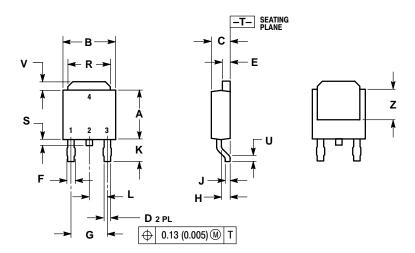


Figure 13. Power Derating

PACKAGE DIMENSIONS

CASE 369A-13 ISSUE W



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.250	5.97	6.35
В	0.250	0.265	6.35	6.73
C	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.033	0.040	0.84	1.01
F	0.037	0.047	0.94	1.19
G	0.180	BSC	4.58 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.102	0.114	2.60	2.89
٦	0.090	BSC	2.29	BSC
R	0.175	0.215	4.45	5.46
S	0.020	0.050	0.51	1.27
U	0.020		0.51	
٧	0.030	0.050	0.77	1.27
Z	0.138		3.51	

ST	YLE	1:
	DIN	4

TYLE 1:
PIN 1. BASE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

STYLE 2:
PIN 1. GATE
2. DRAIN
3. SOURCE
4. DRAIN

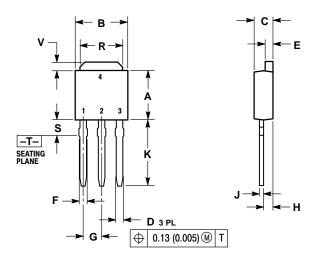
STYLE 3:
PIN 1. ANODE
2. CATHODE
3. ANODE
4. CATHODE

STYLE 4:
PIN 1. CATHODE
2. ANODE
3. GATE
4. ANODE

STYLE 5:
PIN 1. GATE
2. ANODE
3. CATHODE
4. ANODE

PACKAGE DIMENSIONS

CASE 369-07 ISSUE K



- NOTES:
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 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.250	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.033	0.040	0.84	1.01
F	0.037	0.047	0.94	1.19
G	0.090 BSC		2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.175	0.215	4.45	5.46
S	0.050	0.090	1.27	2.28
V	0.030	0.050	0.77	1 27

STYLE 1: PIN 1. 2. 3.	COLLECTOR EMITTER
4.	COLLECTOR

STYLE 2:
PIN 1. GATE
2. DRAIN
3. SOURCE
4. DRAIN

STYLE 3:
PIN 1. ANODE
2. CATHODE
3. ANODE
4. CATHODE

STYLE 4:
PIN 1. CATHODE
2. ANODE
3. GATE
4. ANODE

STYLE 5: PIN 1. GATE 2. ANODE 3. CATHODE 4. ANODE

Notes

Notes

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